Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10565688	MIYANO ET AL.	
Examiner	Art Unit	
Bui-Pho, Pascal M	2878	

SEARCHED					
Class	Subclass	Date	Examiner		
250	234, 227.11, 227.2, 227.24, 227.26, 559.06, 559.29	05/03/07	pmb		
359	664	05/03/07	pmb		
73	105	05/03/07	pmb		

SEARCH NOTES				
Search Notes	Date	Examiner		
Classes 250, 73, 385, 359 - East Search (USPAT, USPGPUB, USOCR, EPO, JPO, DERWENT, IBM_TDB)	05/03/07	pmb		
Consulted with Davienne Monbleau (Class 250)	05/03/07	pmb .		
Consulted with Thanh Luu (Class 250)	05/03/07	pmb		

INTERFERENCE SEARCH				
Subclass	Date	Examine		

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